## Applicant(s)/Patent Under Application/Control No. Reexamination 10/069,118 HATANAKA ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Shin-Hon Chen 2131 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,728,379 04-2004 Ishibashi et al. 380/278 Α US-В US-С US-D US-Ε US-F US-G Н US-USı US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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